

# PSMN0R7-25YLD

N-channel 25 V, 0.72 m $\Omega$ , 300 A logic level MOSFET in LFPAK56 using NextPowerS3 Technology

21 April 2016

**Product data sheet** 

### 1. General description

Logic level gate drive N-channel enhancement mode MOSFET in LFPAK56 package. NextPowerS3 portfolio utilising NXP's unique "SchottkyPlus" technology delivers high efficiency, low spiking performance usually associated with MOSFETS with an integrated Schottky or Schottky-like diode but without problematic high leakage current. NextPowerS3 is particularly suited to high efficiency applications at high switching frequencies.

### 2. Features and benefits

- 100% Avalanche tested at I<sub>(AS)</sub> = 190 A
- Ultra low Q<sub>G</sub>, Q<sub>GD</sub> and Q<sub>OSS</sub> for high system efficiency, especially at higher switching frequencies
- Superfast switching with soft-recovery
- Low spiking and ringing for low EMI designs
- Unique "SchottkyPlus" technology; Schottky-like performance with < 1  $\mu$ A leakage at 25 °C
- Optimised for 4.5 V gate drive
- Low parasitic inductance and resistance
- High reliability clip bonded and solder die attach Power SO8 package; no glue, no wire bonds, qualified to 150 °C
- Wave solderable; exposed leads for optimal visual solder inspection

## 3. Applications

- On-board DC:DC solutions for server and telecommunications
- Secondary-side synchronous rectification in telecommunication applications
- Voltage regulator modules (VRM)
- Point-of-Load (POL) modules
- Power delivery for V-core, ASIC, DDR, GPU, VGA and system components
- Brushed and brushless motor control
- Power OR-ing

### 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	25 °C ≤ T <sub>j</sub> ≤ 150 °C		-	-	25	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; <u>Fig. 2</u>	[1]	-	-	300	Α





Symbol	Parameter	Conditions	Mi	n Typ	Max	Unit
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 1</u>	-	-	158	W
Tj	junction temperature		-5	5 -	150	°C
Static char	acteristics					
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS}$ = 4.5 V; $I_D$ = 25 A; $T_j$ = 25 °C; Fig. 10	-	0.76	0.92	mΩ
		$V_{GS}$ = 10 V; $I_D$ = 25 A; $T_j$ = 25 °C; Fig. 10	-	0.57	0.72	mΩ
Dynamic cl	haracteristics					
Q <sub>G(tot)</sub>	total gate charge	I <sub>D</sub> = 25 A; V <sub>DS</sub> = 12 V; V <sub>GS</sub> = 10 V; Fig. 12; Fig. 13	-	110.2	-	nC
		I <sub>D</sub> = 25 A; V <sub>DS</sub> = 12 V; V <sub>GS</sub> = 4.5 V; Fig. 12; Fig. 13	-	50.9	-	nC
		I <sub>D</sub> = 0 A; V <sub>DS</sub> = 0 V; V <sub>GS</sub> = 10 V	-	45.8	-	nC
$Q_{GD}$	gate-drain charge	I <sub>D</sub> = 25 A; V <sub>DS</sub> = 12 V; V <sub>GS</sub> = 4.5 V; Fig. 12; Fig. 13	-	11.9	-	nC
Source-dra	in diode			1		,
S	softness factor	$I_S = 25 \text{ A}$ ; $dI_S/dt = -100 \text{ A/}\mu\text{s}$ ; $V_{GS} = 0 \text{ V}$ ; $V_{DS} = 12 \text{ V}$ ; $\underline{\text{Fig. 16}}$	-	0.9	-	

<sup>[1] 300</sup>A continuous current has been successfully demonstrated during application tests. Practically the current will be limited by PCB, Thermal design and operating temperature

## 5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		D I
2	S	source		
3	S	source		G—U: A
4	G	Gate		mbb076 S
mb	D	mounting base; connected to drain	1 2 3 4	
			LFPAK56; Power- SO8 (SOT1023)	

## 6. Ordering information

### Table 3. Ordering information

Type number	Package				
	Name	Description	Version		
PSMN0R7-25YLD	LFPAK56; Power-SO8	Plastic single-ended surface-mounted package (LFPAK56); 4 leads	SOT1023		

## 7. Marking

#### Table 4. Marking codes

Type number	Marking code
PSMN0R7-25YLD	0D725L

# 8. Limiting values

### Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
$V_{DS}$	drain-source voltage	25 °C ≤ T <sub>j</sub> ≤ 150 °C		-	25	V
$V_{DGR}$	drain-gate voltage	25 °C ≤ $T_j$ ≤ 150 °C; $R_{GS}$ = 20 kΩ		-	25	V
$V_{GS}$	gate-source voltage			-20	20	V
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 1</u>		-	158	W
I <sub>D</sub>	drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; <u>Fig. 2</u>	[1]	-	300	Α
		V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 100 °C; <u>Fig. 2</u>	[1]	-	235	Α
I <sub>DM</sub>	peak drain current	pulsed; $t_p \le 10 \mu s$ ; $T_{mb} = 25 °C$ ; Fig. 3		-	1482	Α
T <sub>stg</sub>	storage temperature			-55	150	°C
T <sub>j</sub>	junction temperature			-55	150	°C
T <sub>sld(M)</sub>	peak soldering temperature			-	260	°C
V <sub>ESD</sub>	electrostatic discharge voltage	НВМ		2	-	kV
Source-drain	n diode		1			
Is	source current	T <sub>mb</sub> = 25 °C		-	132	Α
I <sub>SM</sub>	peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^{\circ}C$		-	1482	Α
Avalanche ru	uggedness		ı			
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D$ = 300 A; $V_{sup}$ ≤ 25 V; $R_{GS}$ = 50 Ω; $V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; unclamped; $t_p$ = 36 μs		-	174	mJ

Symbol	Parameter	Conditions		Min	Max	Unit
I <sub>AS</sub>	non-repetitive avalanche current	$V_{sup} \le 25 \text{ V}; V_{GS} = 10 \text{ V}; T_{j(init)} = 25 \text{ °C};$ $R_{GS} = 50 \Omega$	[2]	-	190	А

- [1] 300A continuous current has been successfully demonstrated during application tests. Practically the current will be limited by PCB, Thermal design and operating temperature
- [2] Protected by 100% test

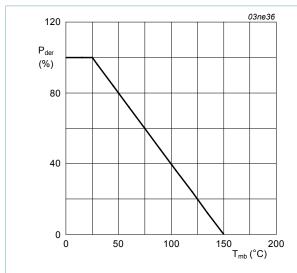
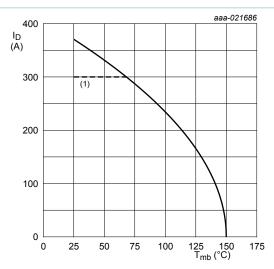


Fig. 1. Normalized total power dissipation as a function of mounting base temperature

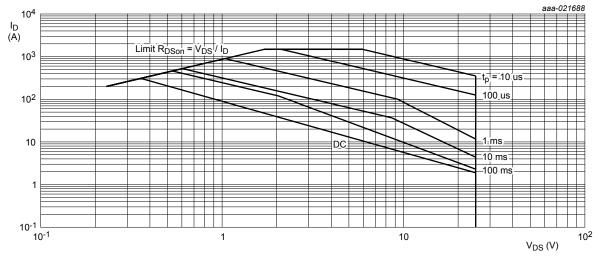
$$P_{der} = \frac{P(tot)}{P_{tot(25^{\circ}C)}} \times 100\%$$



 $V_{GS} \ge 10 \text{ V}$ 

(1) 300A continuous current has been successfully demonstrated during application tests. Practically the current will be limited by PCB, Thermal design and operating temperature

Fig. 2. Continuous drain current as a function of mounting base temperature



 $T_{mb}$  = 25 °C;  $I_{DM}$  is a single pulse

Fig. 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

### 9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	Fig. 4	-	0.59	0.79	K/W
R <sub>th(j-a)</sub> thermal resistance from junction to ambient		Fig. 5	-	50	-	K/W
		<u>Fig. 6</u>	_	125	-	K/W

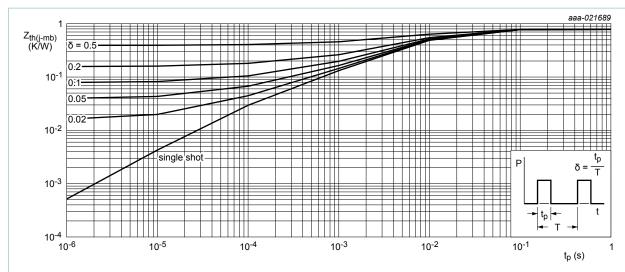


Fig. 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

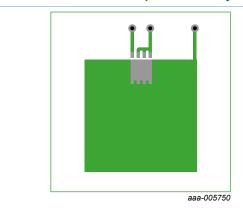


Fig. 5. PCB layout for thermal impedance junction to ambient 1" square pad; FR4 Board; 2oz copper

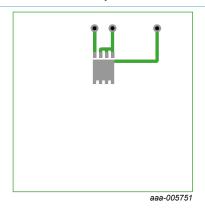


Fig. 6. PCB layout for thermal resistance junction to ambient minimum footprint; FR4 Board; 2oz copper

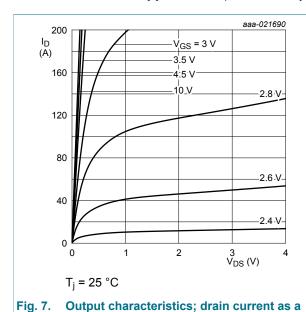
## 10. Characteristics

Table 7 Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	acteristics		'			
V <sub>(BR)DSS</sub>	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	25	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 ^{\circ}C$	22.5	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$	1.2	1.66	2.2	V
$\Delta V_{GS(th)}/\Delta T$	gate-source threshold voltage variation with temperature	25 °C ≤ T <sub>j</sub> ≤ 150 °C	-	-5.1	-	mV/K
I <sub>DSS</sub>	drain leakage current	V <sub>DS</sub> = 20 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	-	1	μΑ
		V <sub>DS</sub> = 20 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 125 °C	-	68.5	-	μΑ
I <sub>GSS</sub>	gate leakage current	V <sub>GS</sub> = 20 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	-	100	nA
		V <sub>GS</sub> = -20 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	-	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; Fig. 10	-	0.76	0.92	mΩ
		V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 150 °C; Fig. 10; Fig. 11	-	-	1.47	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; Fig. 10	-	0.57	0.72	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 150 °C; Fig. 10; Fig. 11	-	-	1.15	mΩ
R <sub>G</sub>	gate resistance	f = 1 MHz	-	1.35	-	Ω
Dynamic ch	naracteristics					
Q <sub>G(tot)</sub>	total gate charge	I <sub>D</sub> = 25 A; V <sub>DS</sub> = 12 V; V <sub>GS</sub> = 10 V; Fig. 12; Fig. 13	-	110.2	-	nC
		I <sub>D</sub> = 25 A; V <sub>DS</sub> = 12 V; V <sub>GS</sub> = 4.5 V; Fig. 12; Fig. 13	-	50.9	-	nC
		I <sub>D</sub> = 0 A; V <sub>DS</sub> = 0 V; V <sub>GS</sub> = 10 V	-	45.8	-	nC
$Q_{GS}$	gate-source charge	I <sub>D</sub> = 25 A; V <sub>DS</sub> = 12 V; V <sub>GS</sub> = 4.5 V;	-	18.8	-	nC
Q <sub>GS(th)</sub>	pre-threshold gate- source charge	Fig. 12; Fig. 13	-	11.9	-	nC
Q <sub>GS(th-pl)</sub>	post-threshold gate- source charge		-	6.9	-	nC
$Q_{GD}$	gate-drain charge		-	11.9	-	nC
V <sub>GS(pl)</sub>	gate-source plateau voltage	I <sub>D</sub> = 25 A; V <sub>DS</sub> = 12 V; <u>Fig. 12</u> ; <u>Fig. 13</u>	-	2.6	-	V

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
C <sub>iss</sub>	input capacitance	V <sub>DS</sub> = 12 V; V <sub>GS</sub> = 0 V; f = 1 MHz;		-	8320	-	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; <u>Fig. 14</u>		-	2982	-	pF
C <sub>rss</sub>	reverse transfer capacitance			-	522	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS}$ = 12 V; $R_L$ = 0.6 $\Omega$ ; $V_{GS}$ = 4.5 V;		-	42.2	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 5 \Omega$		-	48.3	-	ns
t <sub>d(off)</sub>	turn-off delay time			-	53.1	-	ns
t <sub>f</sub>	fall time			-	38.2	-	ns
Q <sub>oss</sub>	output charge	$V_{GS} = 0 \text{ V}; V_{DS} = 12 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}$		-	54	-	nC
Source-dra	ain diode						
V <sub>SD</sub>	source-drain voltage	I <sub>S</sub> = 25 A; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C; <u>Fig. 15</u>		-	0.77	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 25 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = 0 \text{ V};$		-	57.7	-	ns
Qr	recovered charge	V <sub>DS</sub> = 12 V; <u>Fig. 16</u>	[1]	-	83.2	-	nC
t <sub>a</sub>	reverse recovery rise time			-	30.5	-	ns
t <sub>b</sub>	reverse recovery fall time			-	27.2	-	ns
S	softness factor			-	0.9	-	

### [1] includes capacitive recovery



function of drain-source voltage; typical values

Fig. 8. Drain-source on-state resistance as a function of gate-source voltage; typical values

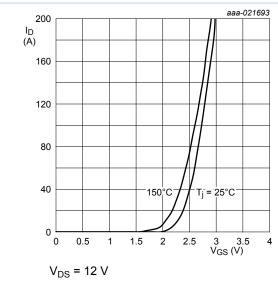


Fig. 9. Transfer characteristics; drain current as a function of gate-source voltage; typical values

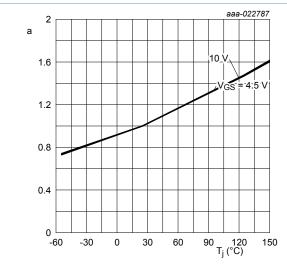


Fig. 11. Normalized drain-source on-state resistance factor as a function of junction temperature

$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

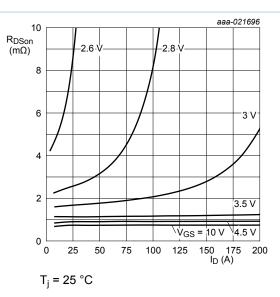
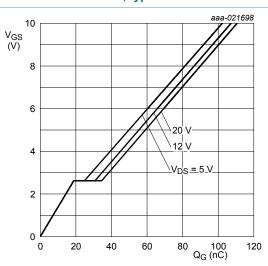


Fig. 10. Drain-source on-state resistance as a function of drain current; typical values



 $T_i = 25 \,^{\circ}C; I_D = 25 \,^{\circ}A$ 

Fig. 12. Gate-source voltage as a function of gate charge; typical values

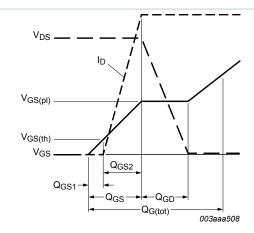
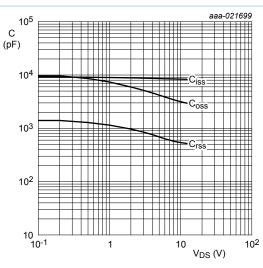


Fig. 13. Gate charge waveform definitions



 $V_{GS} = 0 V; f = 1 MHz$ 

Fig. 14. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

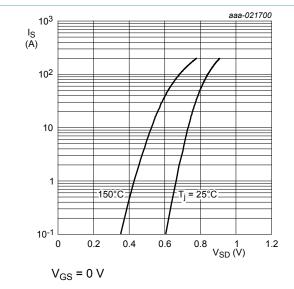


Fig. 15. Source-drain (diode forward) current as a function of source-drain (diode forward) voltage; typical values

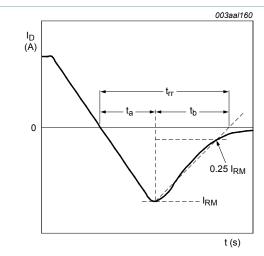
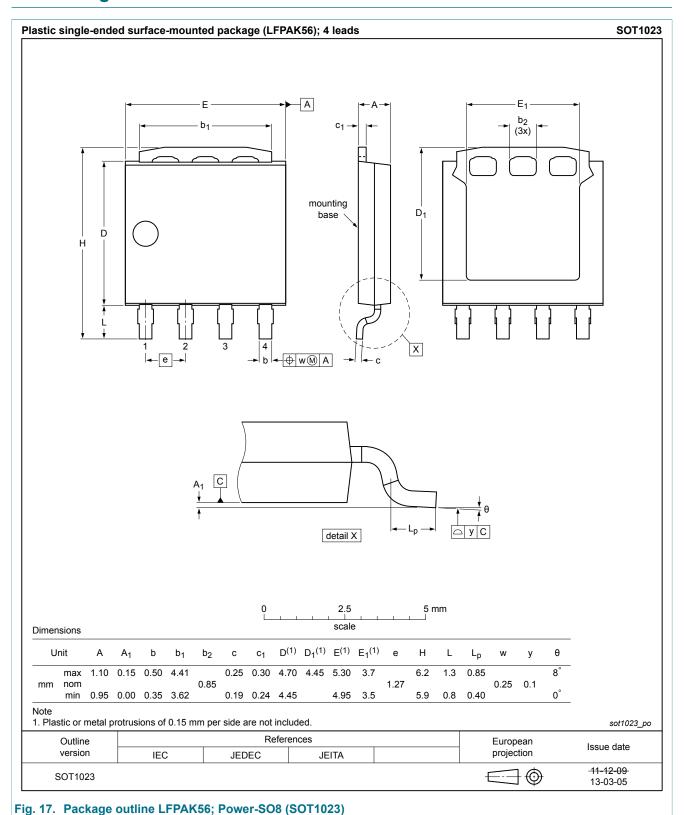


Fig. 16. Reverse recovery timing definition

## 11. Package outline



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MC13211R2 PCA9518PW,112 LFSTBEB865X MC33399PEFR2 PCA9551PW,112 MC34825EPR2 CBTW28DD14AETJ PCF8583P
MC68340AB16E MC8640DTVJ1250HE EVBCRTOUCH MC9S08PT16AVLC MC9S08PT8AVTG MC9S08SH32CTL MCF54415CMJ250
MCIMX6Q-SDB MCIMX6SX-SDB 74ALVC125BQ,115 74HC4050N 74HC4514N MK21FN1M0AVLQ12 MKV30F128VFM10 FRDMK66F FRDM-KW40Z FRDM-MC-LVBLDC PESD18VF1BSFYL PMF63UNEX PSMN4R0-60YS,115 HEF4028BPN RAPPID-567XFSW
MPC565MVR56 MPC574XG-176DS MPC860PCVR66D4 BT137-600E BT139X-600.127 BUK7628-100A118 BUK765R0-100E.118
BZT52H-B9V1.115 BZV85-C3V9.113 BZX79-C47.113 P5020NSE7VNB S12ZVML12EVBLIN SCC2692AC1N40 LPC1785FBD208K
LPC2124FBD64/01 LS1020ASN7KQB LS1020AXN7HNB LS1020AXN7KQB LS1043ASE7PQA T1023RDB-PC